

- Members of the Texas Instruments *Widebus™* Family
- State-of-the-Art *EPIC-IIIB™* BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce) < 1 V at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs (-32 -mA I_{OH} , 64 -mA I_{OL})
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

description

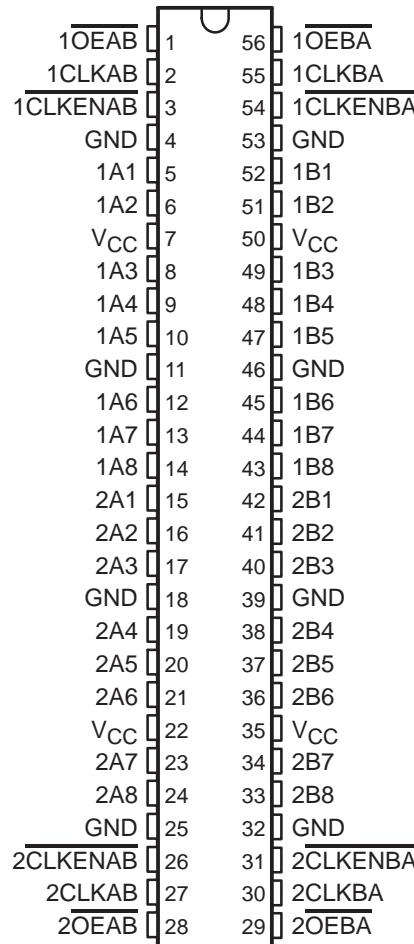
The 'ABT16470 are 16-bit registered transceivers that contain two sets of D-type flip-flops for temporary storage of data flowing in either direction. The 'ABT16470 can be used as two 8-bit transceivers or one 16-bit transceiver. Separate clock (CLKAB or CLKBA) and output-enable (\overline{OEAB} or \overline{OEBA}) inputs are provided for each register to permit independent control in either direction of data flow.

To avoid false clocking of the flip-flops, clock enable (CLKEN) should not be switched from high to low while CLK is high.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16470 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ABT16470 is characterized for operation from -40°C to 85°C .

SN54ABT16470 . . . WD PACKAGE
SN74ABT16470 . . . DGG OR DL PACKAGE
(TOP VIEW)



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**SN54ABT16470, SN74ABT16470
16-BIT REGISTERED TRANSCEIVERS
WITH 3-STATE OUTPUTS**

SCBS085E – FEBRUARY 1991 – REVISED MAY 1997

FUNCTION TABLE†

INPUTS				OUTPUT B
<u>CLKENAB</u>	<u>CLKAB</u>	<u>OEAB</u>	A	
H	X	X	X	Z
X	X	H	X	Z
L	L	L	X	B_0^{\ddagger}
L	↑	L	L	L
L	↑	L	H	H

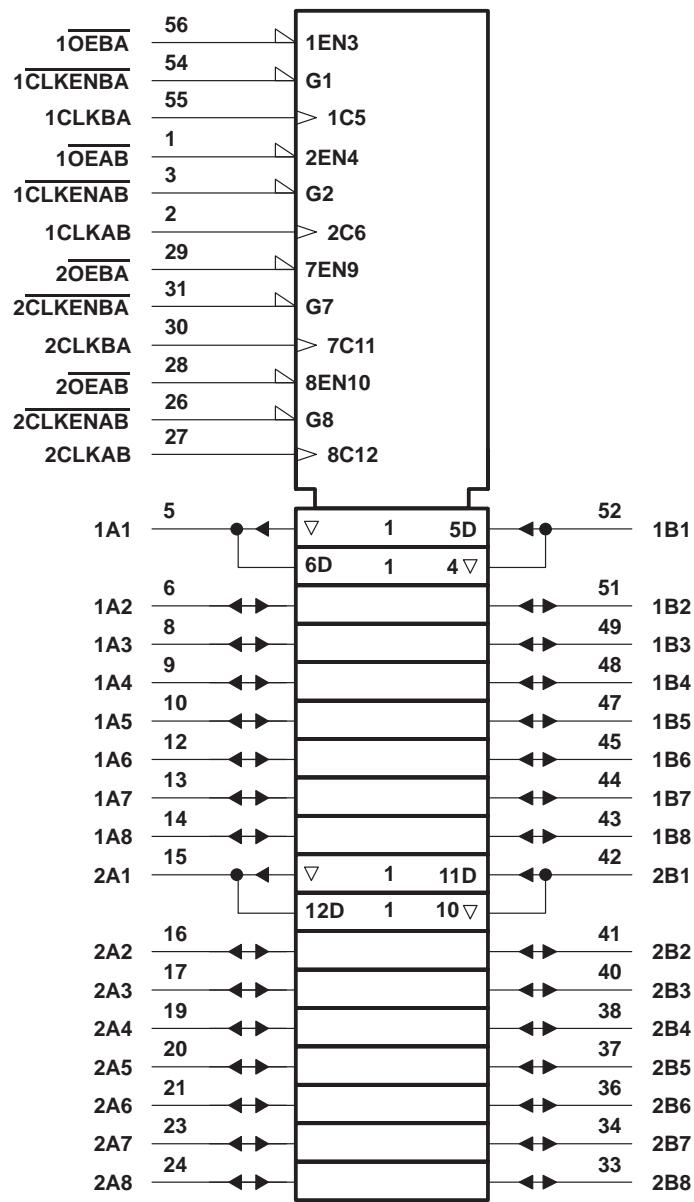
† A-to-B data flow is shown; B-to-A flow is similar but uses CLKENBA, CLKBA, and OEBA.

‡ Output level before the indicated steady-state input conditions were established



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logic symbol†

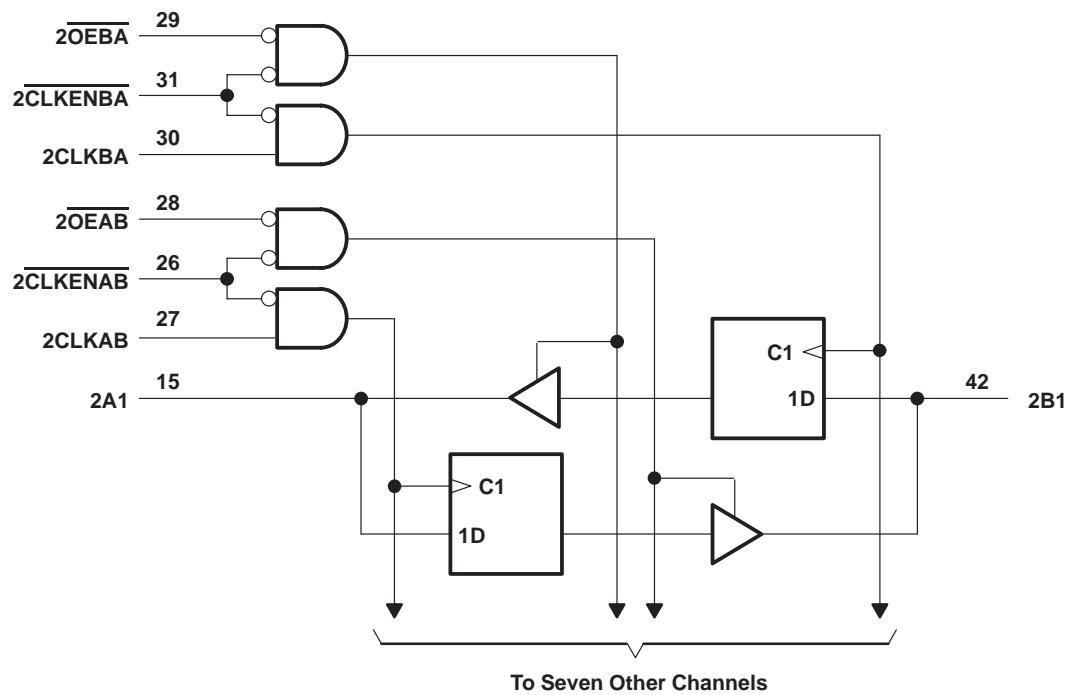
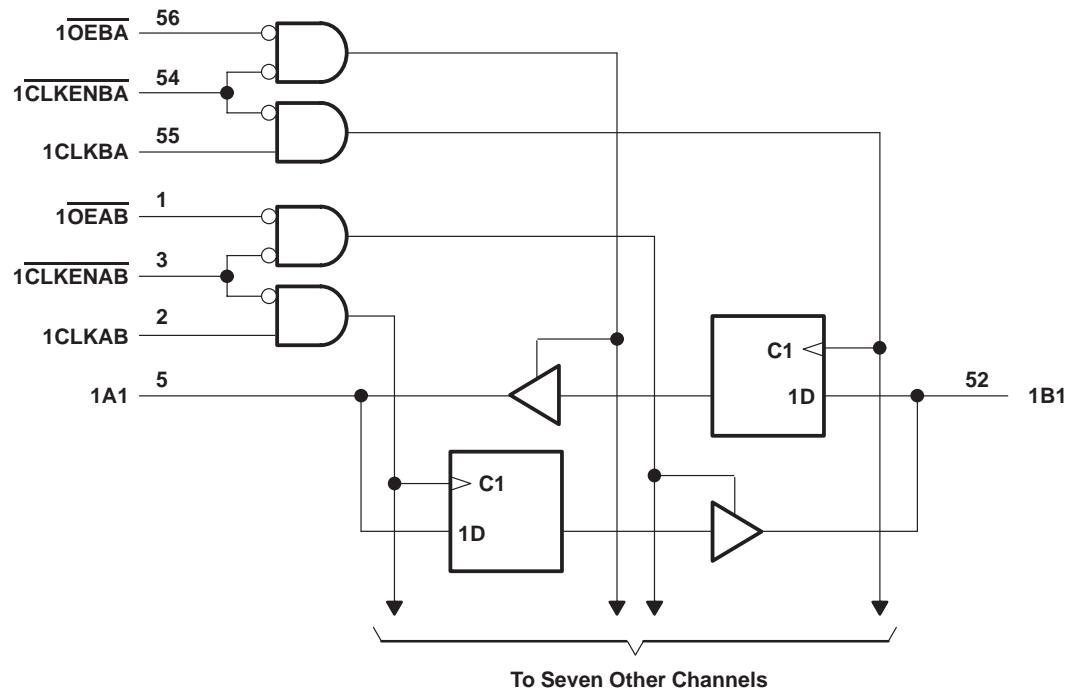


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 3)

		SN54ABT16470		SN74ABT16470		UNIT
		MIN	MAX	MIN	MAX	
V _{CC}	Supply voltage	4.5	5.5	4.5	5.5	V
V _{IH}	High-level input voltage	2		2		V
V _{IL}	Low-level input voltage			0.8	0.8	V
V _I	Input voltage	0	V _{CC}	0	V _{CC}	V
I _{OH}	High-level output current			-24	-32	mA
I _{OL}	Low-level output current			48	64	mA
Δt/ΔV	Input transition rise or fall rate	Outputs enabled		10	10	ns/V
T _A	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	TA = 25°C			SN54ABT16470		SN74ABT16470		UNIT
		MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
VIK	V _{CC} = 4.5 V, I _I = -18 mA			-1.2		-1.2		-1.2	V
V _{OH}	V _{CC} = 4.5 V, I _{OH} = -3 mA	2.5			2.5		2.5		V
	V _{CC} = 5 V, I _{OH} = -3 mA	3			3		3		
	V _{CC} = 4.5 V, I _{OH} = -24 mA	2			2				
	I _{OH} = -32 mA	2*					2		
V _{OL}	V _{CC} = 4.5 V	I _{OL} = 48 mA		0.55		0.55			V
		I _{OL} = 64 mA		0.55*				0.55	
V _{hys}		100							mV
I _I	Control inputs	V _{CC} = 5.5 V, V _I = V _{CC} or GND		±1		±1		±1	µA
	A or B ports			±100		±100		±100	
I _{OZH} ‡	V _{CC} = 5.5 V, V _O = 2.7 V			50		50		50	µA
I _{OZL} ‡	V _{CC} = 5.5 V, V _O = 0.5 V			-50		-50		-50	µA
I _{off}	V _{CC} = 0, V _I or V _O ≤ 4.5 V			±100				±100	µA
I _{CEX}	V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high		50		50		50	µA
I _O §	V _{CC} = 5.5 V, V _O = 2.5 V		-50	-100	-200	-50	-200	-50	mA
I _{CC}	A or B ports	V _{CC} = 5.5 V, I _O = 0, V _I = V _{CC} or GND	Outputs high		2		2		mA
			Outputs low		35		35		
			Outputs disabled		2		2		
ΔI _{CC} ¶	V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND			0.5		0.5		0.5	mA
C _i	Control inputs	V _I = 2.5 V or 0.5 V		3					pF
C _{io}	A or B ports	V _O = 2.5 V or 0.5 V		8.5					pF

* On products compliant to MIL-PRF-38535, this parameter does not apply.

† All typical values are at V_{CC} = 5 V.

‡ The parameters I_{OZH} and I_{OZL} include the input leakage current.

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

¶ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		V _{CC} = 5 V, TA = 25°C	SN54ABT16470		SN74ABT16470		UNIT
			MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		0	150	0	150	MHz
t _w ‡	Pulse duration, CLKAB or CLKBA high or low	3.3		3.3		3.3	ns
t _{su}	Setup time, data before CLKAB↑ or CLKBA↑	4		4		4	ns
t _h	Hold time, data after CLKAB↑ or CLKBA↑	1		1		1	ns

This parameter is characterized, but not production tested.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$			SN54ABT16470		SN74ABT16470		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f_{max}			150			150		150		MHz
t_{PLH}	CLK	A or B	1.4	3.1	4.8	1.4	5.1	1.4	4.9	ns
t_{PHL}			1.3	3.2	4.6	1.3	5.1	1.3	4.9	
t_{PZH}	\overline{OE}	A or B	1	3.1	4.3	1	5	1	4.9	ns
t_{PZL}			1.2	3.6	5.8	1.2	6.9	1.2	6.8	
t_{PHZ}	\overline{OE}	A or B	1.9	3.7	4.9	1.9	6	1.9	5.5	ns
t_{PLZ}			1.6	3.3	4.8	1.6	5.4	1.6	5.3	
t_{PZH}	\overline{CLKEN}	A or B	1	3.4	4.6	1	5.8	1	5.7	ns
t_{PZL}			1.2	3.9	6	1.2	7.3	1.2	7.2	
t_{PHZ}	\overline{CLKEN}	A or B	1.7	3.9	5.2	1.7	6.2	1.7	5.8	ns
t_{PLZ}			1.5	3.6	5.3	1.5	5.5	1.5	5.4	

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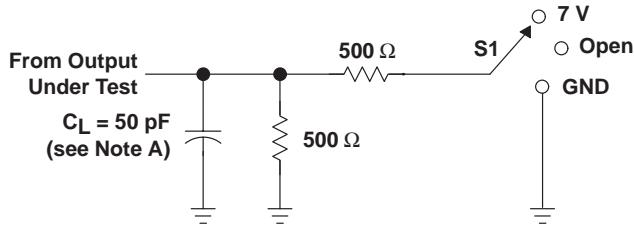


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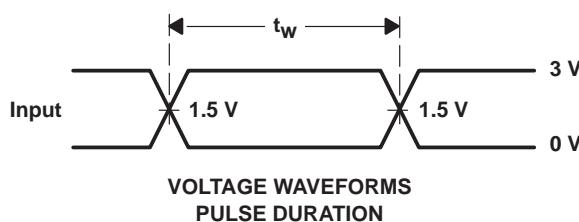
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PARAMETER MEASUREMENT INFORMATION

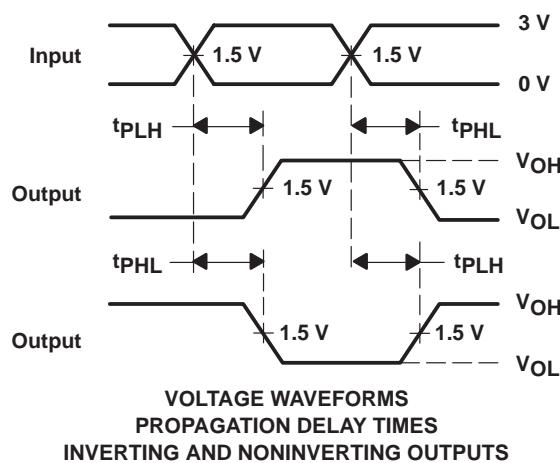
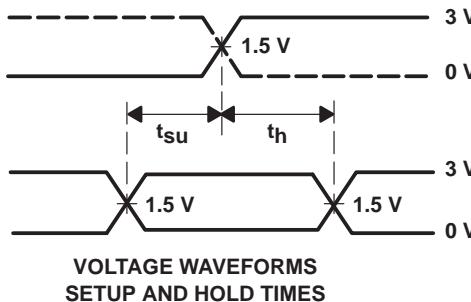


TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open

LOAD CIRCUIT



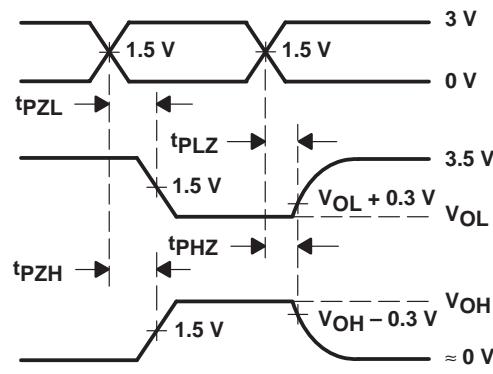
Timing Input



Output Control

Output Waveform 1
S1 at 7 V
(see Note B)

Output Waveform 2
S1 at Open
(see Note B)



- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_r \leq 2.5$ ns, $t_f \leq 2.5$ ns.
 D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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